

PRISM/PRIME

the Advanced Muon Beam
and
the Experiment Searching for
 μ -e Conversion with 10^{-18} Sensitivity

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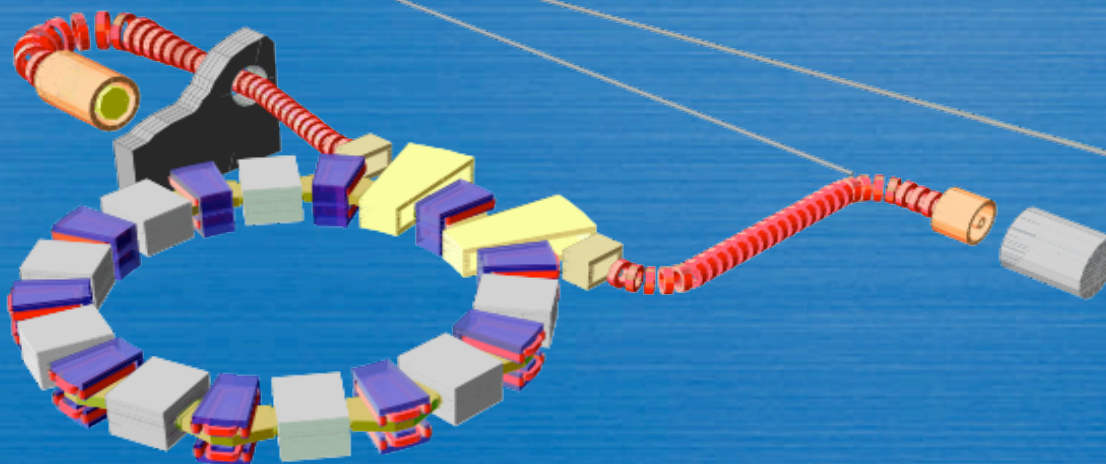
On behalf of the PRISM Collaboration

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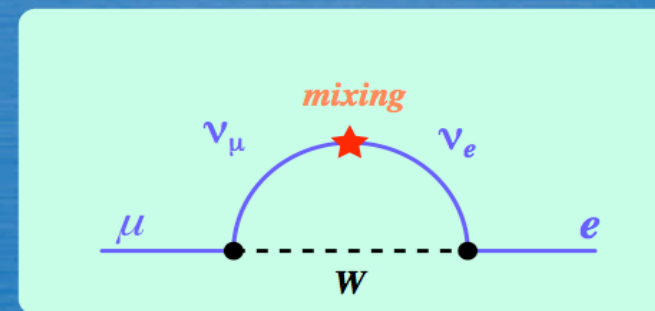
- Muon Lepton Flavor Violation (μ -LFV)
- $\mu \rightarrow e \gamma$ Decay and μ -e Conversion
- PRISM
- PRIME
- Conclusion



Muon LFV

- Charged leptons do mix via ν oscillation.
- However, it is very weak for charged leptons due to GIM-like mechanism.

$$B(\mu \rightarrow e\gamma) = \frac{3\alpha}{32\pi} \sum_i \left| U_{\mu i} U_{ei}^* \frac{m_{\nu_i}^2}{M_W^2} \right|^2 \simeq 10^{-60} \left(\frac{m_\nu}{10^{-2} \text{ eV}} \right)^4$$



- Thus, observation of μ - e transition immediately indicates physics beyond the Standard Model of particle physics.

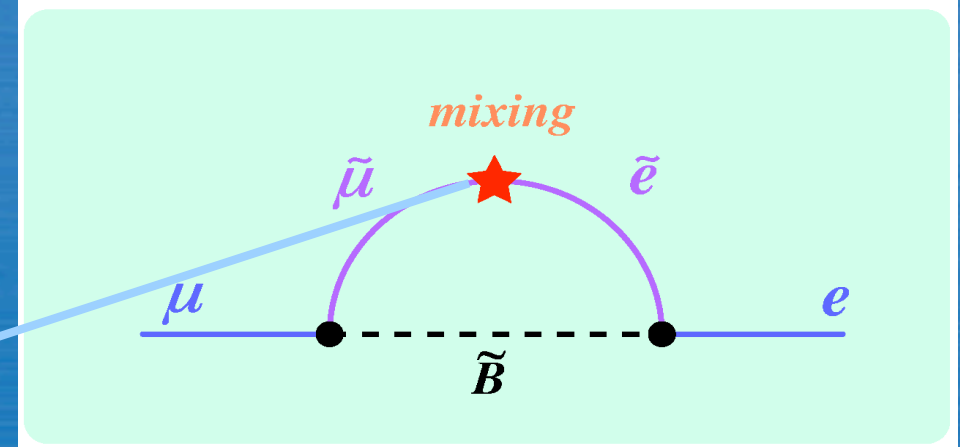
SUSY and slepton mixing

- Large top Yukawa couplings result in sizable off-diagonal components in a slepton mass matrix through radiative corrections, and that implies observable levels of LFV in some models of SUSY-GUT

Barbieri and Hall, 1994

$$\begin{pmatrix} m_{\tilde{e}\tilde{e}}^2 & \Delta m_{\tilde{e}\tilde{\mu}}^2 & \Delta m_{\tilde{e}\tilde{\tau}}^2 \\ \Delta m_{\tilde{\mu}\tilde{e}}^2 & m_{\tilde{\mu}\tilde{\mu}}^2 & \Delta m_{\tilde{\mu}\tilde{\tau}}^2 \\ \Delta m_{\tilde{\tau}\tilde{e}}^2 & \Delta m_{\tilde{\tau}\tilde{\mu}}^2 & m_{\tilde{\tau}\tilde{\tau}}^2 \end{pmatrix}$$

LFV diagram in SUSY



Charged LFV

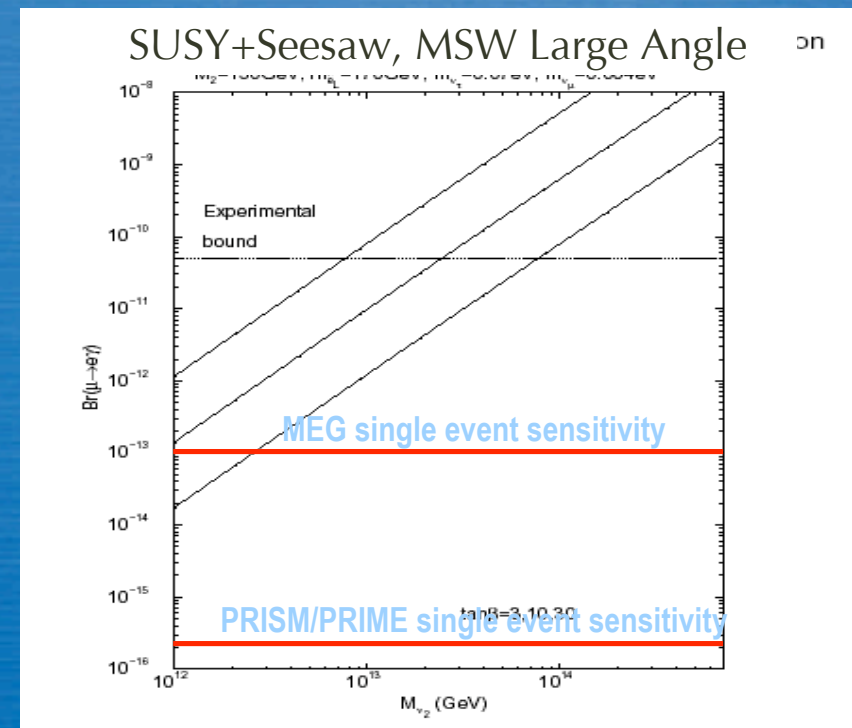
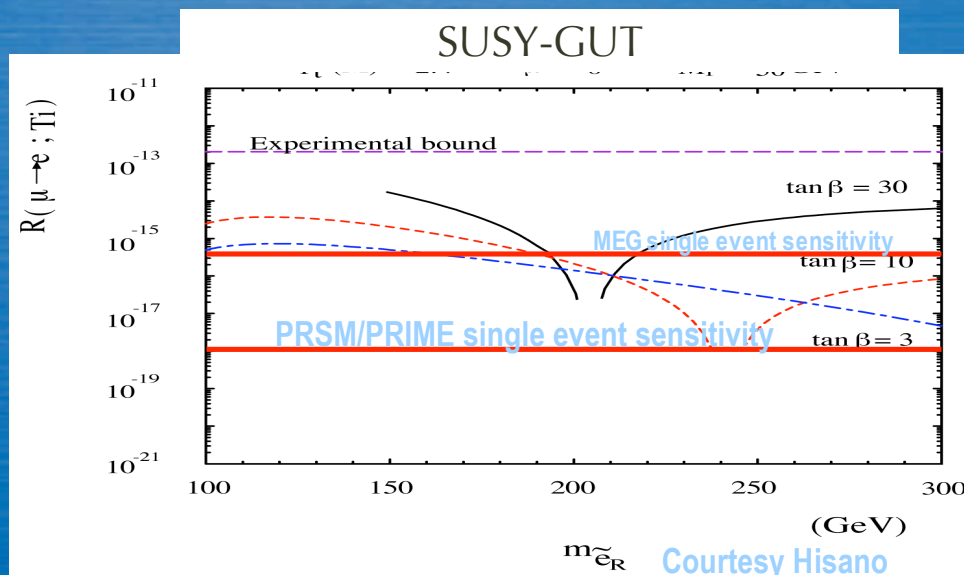


Physics of slepton Mass Matrix



SUSY-GUT & SUSY Seesaw Prediction

Process	Current Limit	SUSY-GUT level
$\mu N \rightarrow e N$	10^{-13}	10^{-16}
$\mu \rightarrow e \gamma$	10^{-11}	10^{-14}
$\tau \rightarrow \mu \gamma$	10^{-6}	10^{-9}



μ -e Conversion Process

■ Muonic Atom (1S state)

$$\mu^- + (A, Z) \rightarrow \nu_\mu + (A, Z - 1)$$

Muon Decay in Orbit

$$\mu^- \rightarrow e^- \nu \bar{\nu}$$

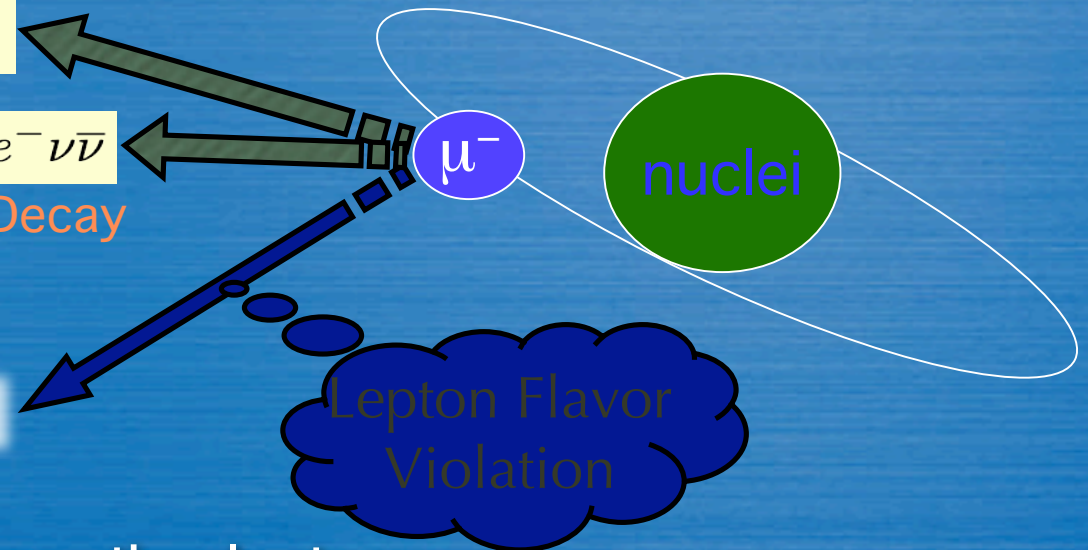
Michel Decay

■ μ -e Conversion

$$\mu^-(A, Z) \rightarrow e^- + (A, Z)$$

Coherent Process

- Emission of mono-energetic electron
 $E_{\max} = (M_\mu - B_\mu) \text{ MeV } (\sim 105 \text{ MeV})$
- $R_{\mu e} \equiv \Gamma(\mu N \rightarrow e N) / \Gamma(\mu N \rightarrow \nu_\mu N(Z-1))$

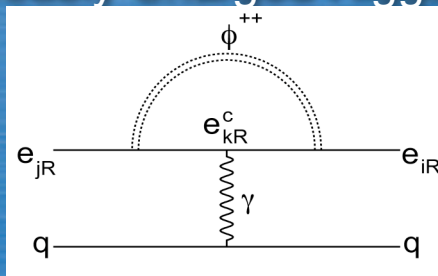


Physics in μ -e Conversion

- SUSY-GUT
- SUSY Seesaw

- $BR \sim 10^{-15}$

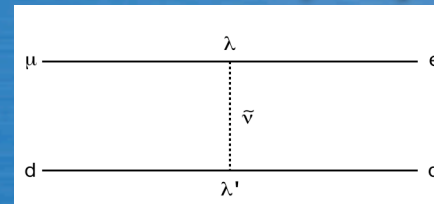
- Doubly Charged Higgs Boson



- Logarithmic enhancement in a loop diagram for $\mu N \rightarrow e N$, not for $\mu \rightarrow e \gamma$
- $\Lambda \sim 1$ PeV for PRISM/PRIME
 - M. Raidal and A. Santamaria, PLB 421 (1998) 250

$$\Lambda > 3000 \text{ TeV} \sqrt{\eta_q}$$

- SUSY with R-parity Violation



- $|\lambda'_{211} \lambda_{212}| < 6 \times 10^{-12}$ for PRISM/PRIME
- Faessler et al., NPB 587 (2000) 25-44

- Leptquarks

- Heavy Z'

- $M_{Z'} > (5-100) \text{ TeV}$ for $R_{\mu e} \sim 10^{-16}$
- J. Bernabeu et al., NPB 409 (1993) 69-86

- Compositeness

- Multi-Higgs Models

η_q : model dependent combination of couplings, mixings, etc.



$\mu^- N \rightarrow e^- N$ vs. $\mu \rightarrow e \gamma$

- $\mu^- N \rightarrow e^- N$
(PRISM/PRIME, MECO)
- Sensitive to non-photon process
- $\mu \rightarrow e \gamma$
(MEG)
- $B(\mu \rightarrow e \gamma) = 200 \times B(\mu^- N \rightarrow e^- N)$
for photonic process

Physics is Complementary

- μ^- beam < μ^+ beam
- No accidental backgrounds
- Requires "state-of-the-art" muon beam
- Surface muon beam exists
- Accidental background dominates
- Requires "state-of-the-art" Detector

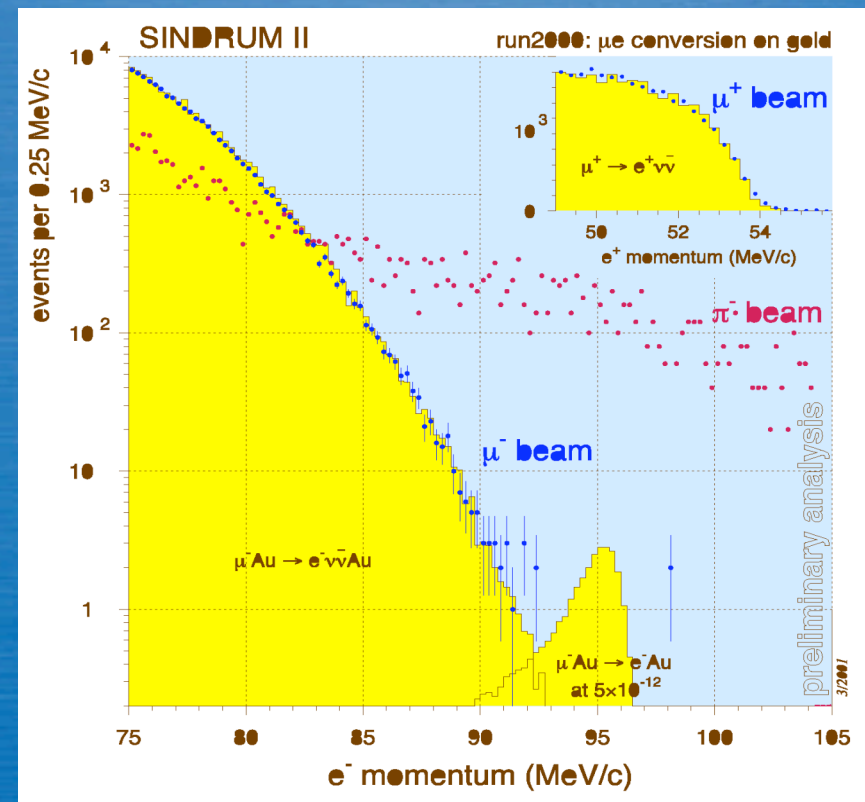
Different Experimental Techniques

Different potential systematics

Both are "must do" to maximize potential discovery

Backgrounds in $\mu^- N \rightarrow e^- N$

- No accidental backgrounds
- Radiative pion capture
 - Must suppress pions in beam
- Muon Decay in Orbit
 - $E_{\text{max}} = E_{\text{LFV}}$
 $\frac{dN}{dE_{\text{MDO}}} \propto (E_{\text{LFV}} - E_{\text{MDO}})^5$
 - $N_{\text{bg}} = 0.25$ for $R_{\mu e} = 10^{-18}$
 - $\Delta E_e = 500$ keV FWHM
 given by ΔE uncertainty in
 muon stopping target

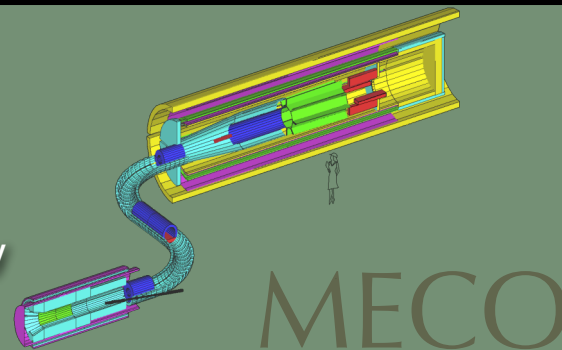




PRISM/PRIME for $\mu^- N \rightarrow e^- N$

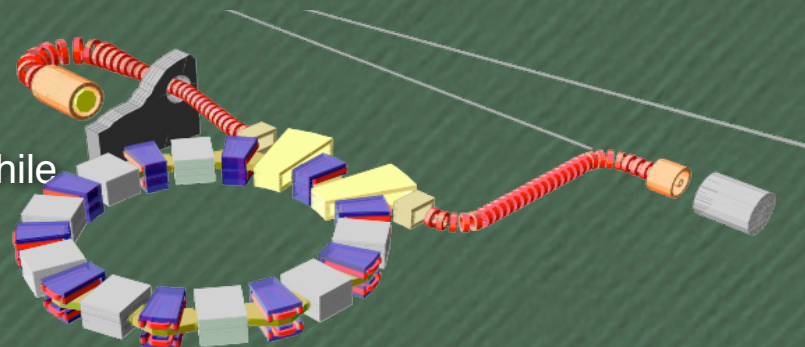
A good beam is essential for a good $\mu^- N \rightarrow e^- N$ exp.

- High muon intensity
 - More than $10^{12} \mu^-/\text{sec}$
- Pulsed beam
 - Rejection of background coming from proton (mostly pions)



MECO

- Narrow energy spread
 - $\Delta E/E = \pm 0.5 \sim 1.0 \text{ MeV}$
 - Thinner muon-stopping target
 - Thus, better e^- momentum/energy resolution while keeping muon stopping efficiency
- Less beam contamination
 - Practically no pion contamination
 - $\pi/\mu \sim 10^{-18}$

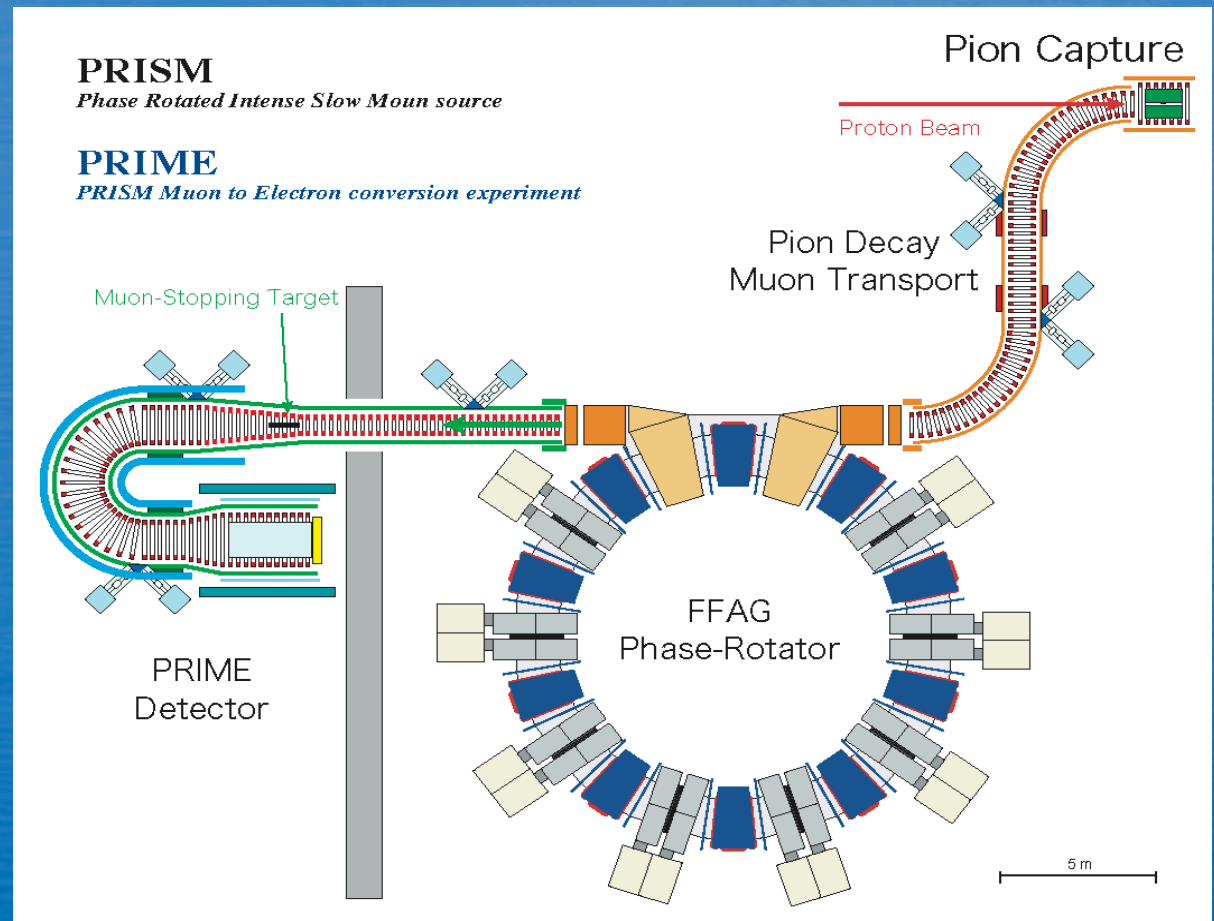


PRISM/PRIME

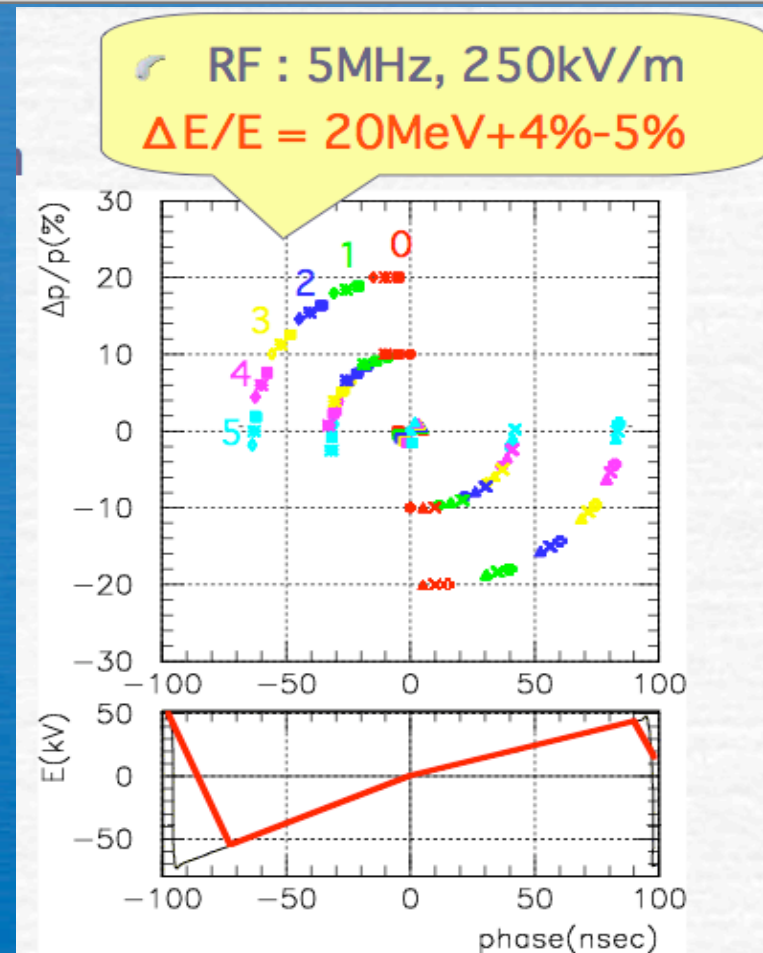
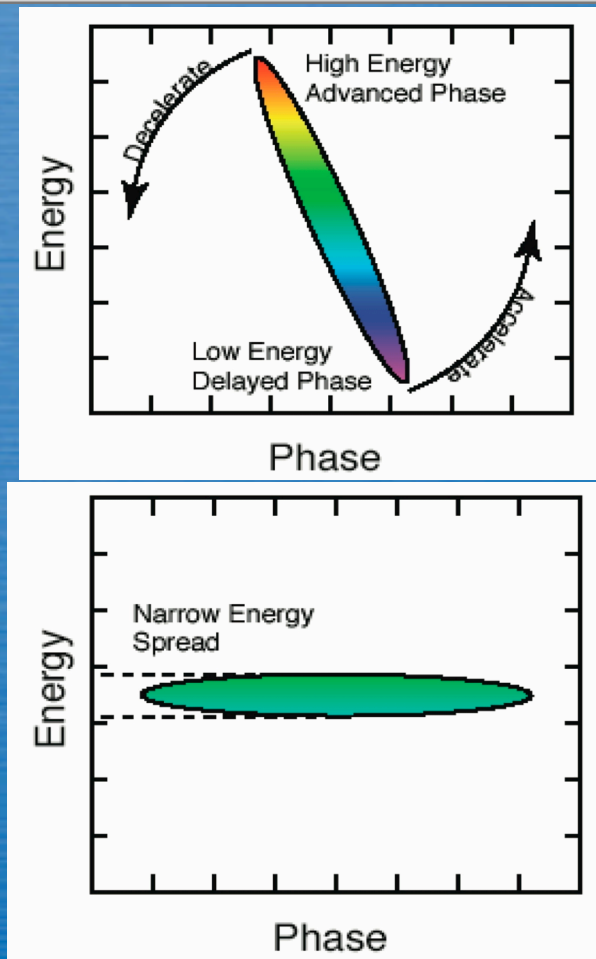
PRISM

Phase-Rotated Intense Slow Muon source

- High Intensity
 - 10^{11} - 10^{12} μ^\pm/sec
- High Brightness
 - $\pm 0.5 \sim 1.0$ MeV
- High Purity
 - $\pi/\mu \sim 10^{-18}$
- Low Energy
 - 20 MeV (68 MeV/c)
- Pulsed
 - 100 Hz



What is the Phase-Rotation





PRIME

PRism Muon-Electron conversion

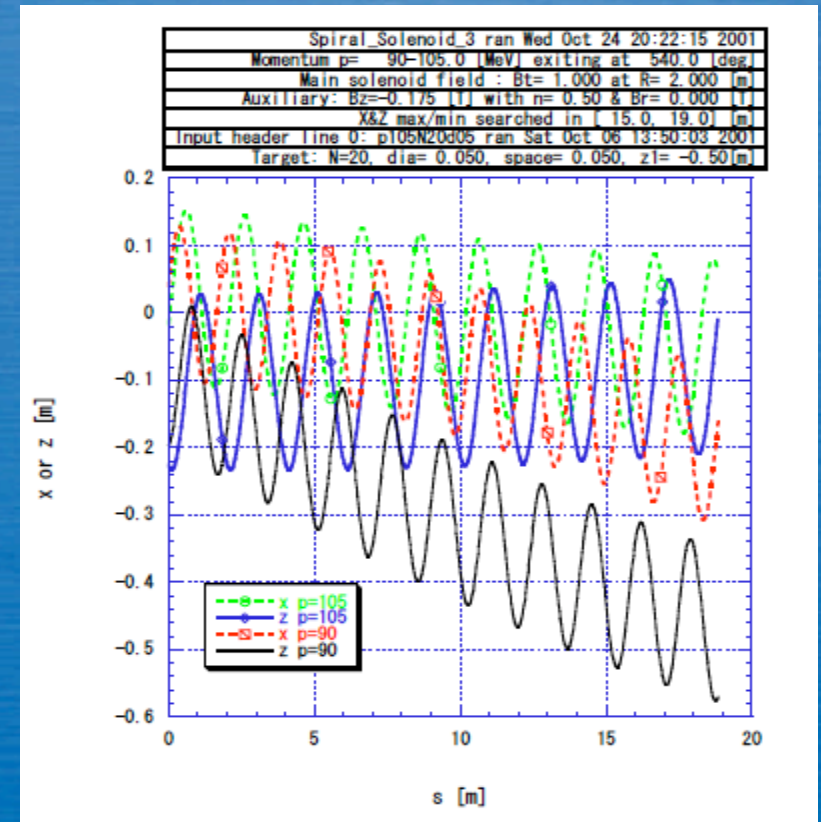
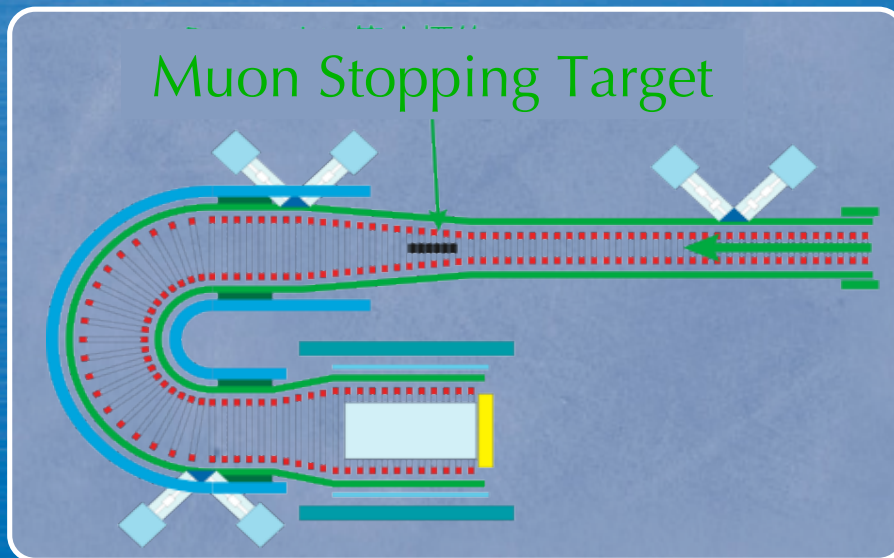
- Utilizes the advantage of PRISM Beam
 - High Intensity, High Brightness, High Purity
 - Pulse Frequency: 100 Hz
 - Pulse Duration: 200 ns
 - Instantaneous Rate: 10^{10} muons/sec
- Unwanted particles must be physically suppressed.
 - Curved-Solenoid Muon Transport
(from MECO)

Spiral Solenoid Spectrometer

- Vertical drift of charged particles in torus magnetic field

$$\frac{1}{0.3B} \frac{s}{R} \frac{(p_l^2 + \frac{1}{2}p_t^2)}{p_l}$$

D: drift distance
B: magnetic field
s/R: bending angle
pl: longitudinal momentum
pt: transverse momentum



IC'05



Sensitivity

- Proton Driver: 0.75 MW
- Muon yield depends on technology choice in pion capture section, such as target material, magnetic field strength:
typically $0.3 \sim 2 \times 10^{11} \mu^-/\text{sec}$
- PRIME acceptance: 40%
- A few nominal years (several 10^7sec) of run
- **Single Event Sensitivity $\sim 10^{-18}$**



Conclusion

- μ - e Conversion is very important.
- Super muon beam, PRISM, for μ - e Conversion.
- The experiment that utilizes PRISM beam, PRIME, could search for μ - e conversion down to 10^{-18} level.

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